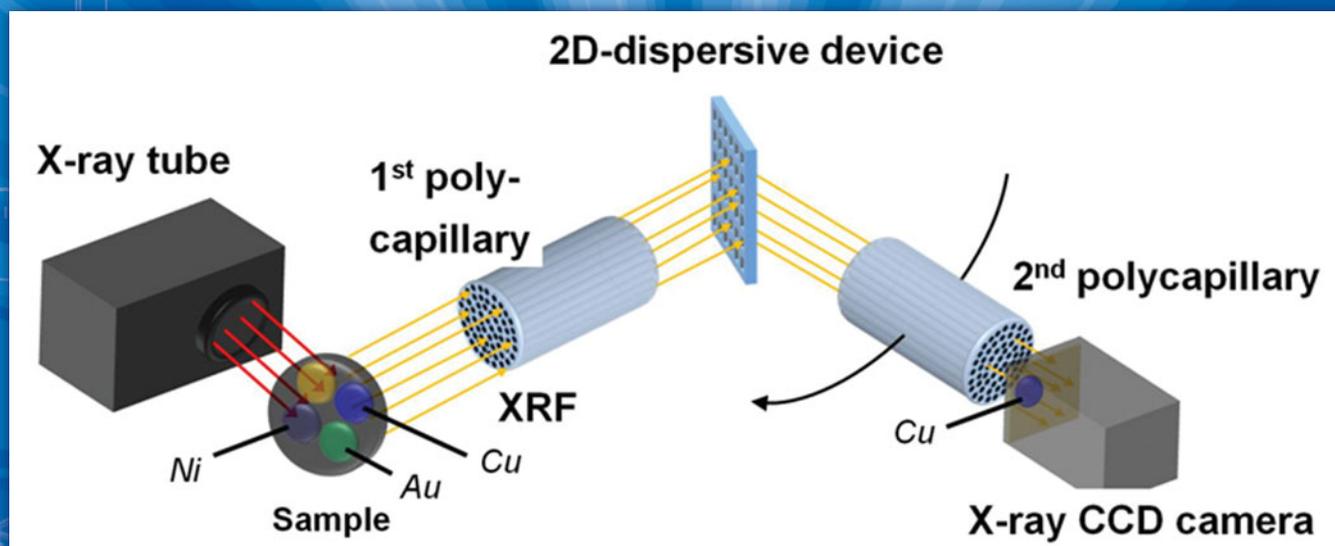
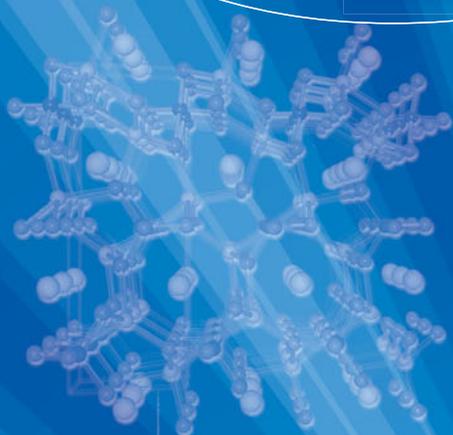


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EDITORIALS

- Ting C. Huang Special issue on representative articles from 2011 Denver X-ray Conference 69
- Tom Blanton and George Havrilla Sixtieth Denver X-ray Conference and selected papers for the special June *Powder Diffraction* issue 70

TECHNICAL ARTICLES

- Takashi Ohmori, Masatoshi Hatayama, Tadayuki Ohchi, Hisashi Ito, Hisataka Takenaka, and Kouichi Tsuji Development of X-ray 2D dispersive device for WD-XRF imaging spectrometer 71
- Martina Schmeling, Donald S. Burnett, Amy J. G. Jurewicz, and Igor V. Veryovkin Steps toward accurate large-area analyses of Genesis solar wind samples: evaluation of surface cleaning methods using total reflection X-ray fluorescence spectrometry 75
- Michael J. Haugh, Michael R. Charest, Patrick W. Ross, Joshua J. Lee, Marilyn B. Schneider, Nathan E. Palmer, and Alan T. Teruya Calibration of X-ray imaging devices for accurate intensity measurement 79
- F. J. Cadieu, I. Vander, Y. Rong, and R. W. Zuneska X-ray measurements of nanometer-thick tantalum oxide and hafnium oxide films on silicon substrates for thickness and composition determination 87
- Conal E. Murray, E. Todd Ryan, Paul R. Besser, Christian Witt, Jean L. Jordan-Sweet, and Michael F. Toney Understanding stress gradients in microelectronic metallization 92
- Peter W. Stephens, James A. Kaduk, Thomas N. Blanton, David R. Whitcomb, Scott T. Misture, and Manju Rajeswaran Structure determination of the silver carboxylate dimer $[\text{Ag}(\text{O}_2\text{C}_{20}\text{H}_{39})]_2$, silver arachidate, using powder X-ray diffraction methods 99
- Thomas N. Blanton, and Debasis Majumdar X-ray diffraction characterization of polymer intercalated graphite oxide 104
- Mark A. Rodriguez, Paul G. Kotula, James J. M. Griego, Jason E. Heath, Stephen J. Bauer, and Daniel E. Wesolowski Multivariate statistical analysis of micro-X-ray fluorescence spectral images 108
- Thomas Gnäupel-Herold A software for diffraction stress factor calculations for textured materials 114
- Eric N. Coker, Mark A. Rodriguez, Andrea Ambrosini, James E. Miller, and Ellen B. Stechel Using *in-situ* techniques to probe high-temperature reactions: thermochemical cycles for the production of synthetic fuels from CO_2 and water 117
- Shouwen Shen, Syed R. Zaidi, Bader A. Mutairi, Ahmed A. Shehry, Husin Sitepu, Saud A. Hamoud, Fahad S. Khaldi, and Fatimah A. Edhaim Quantitative XRD bulk and clay mineralogical determination of paleosol sections of Unayzah and Basal Khuff clastics in Saudi Arabia 126

J. L. Garin, and R. L. Mannheim	Rietveld quantitative analysis of cast super duplex steel	131
Roy G. Baggerly	Electrolytic phase extraction: a useful technique to evaluate precipitates in nitinol	136

INTERNATIONAL REPORT

Tess Kozul	2012 ICDD Annual Spring Meetings	140
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CALENDAR

Calendar of Forthcoming Meetings <i>Powder Diffraction June 2012</i>	147
Calendar of Short Courses and Workshops <i>Powder Diffraction June 2012</i>	148
Denver X-ray Conference Program	149
Cumulative Author Index	169

Powder Diffraction

An International Journal of Materials Characterization

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On the cover: WDXRF spectrometer equipped with 2D dispersive device, polycapillary optics and x-ray CCD camera. (Courtesy of Takashi Ohmori, Masatoshi Hatayama, Tadayuki Ohchi, Hisashi Ito, Hisataka Takenaka, and Kouichi Tsuji).

Powder Diffraction is a quarterly journal published by the JCPDS-International Centre for Diffraction Data through Cambridge University Press.

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For advertising rates and schedules contact Cambridge University Press Advertising Sales. Orders, advertising copy, and offset negatives should be sent to: Advertising Sales, Cambridge University Press, 32 Avenue of the Americas, New York, NY, 10013-2473, U.S.A.; Phone: 212-924-3900; Fax: 212-924-3900. Email: USAdSales@cambridge.org.

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Subscription rates to Eastern Hemisphere include air freight service.

Back-Number Prices. 2012 single copies: \$62.

Subscription, renewals, and address changes should be addressed to Subscription Fulfillment, *Powder Diffraction*, Cambridge University Press, 100 Brook Hill Drive, West Nyack, NY 10013-2113 (for U.S.A., Canada, and Mexico); or Cambridge University Press, The Edinburgh Building, Shaftsbury Road, Cambridge, CB2 8RU, Cambridge, England (for UK and elsewhere). Allow at least six weeks advance notice. For address changes please send both old and new addresses and, if possible, include a mailing label from the wrapper of a recent issue.

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Powder Diffraction (ISSN: 0885-7156) is published quarterly (4X annually) by the JCPDS-International Centre for Diffraction Data through Cambridge University Press, 32 Avenue of the Americas, New York, NY 10013-2473. POSTMASTER: Send address changes to *Powder Diffraction*, Cambridge University Press, 100 Brook Hill Drive West Nyack, NY 10994-2113, USA. Periodicals postage paid in New York, NY and additional mailing offices.

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